

**SN74ALVCH16721**  
**3.3-V 20-BIT FLIP-FLOP**  
**WITH 3-STATE OUTPUTS**

SCES052D – JULY 1995 – REVISED FEBRUARY 1999

- **Member of the Texas Instruments Widebus™ Family**
- **EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages**

**description**

This 20-bit flip-flop is designed specifically for 1.65-V to 3.6-V  $V_{CC}$  operation.

The 20 flip-flops of the SN74ALVCH16721 are edge-triggered D-type flip-flops with qualified clock storage. On the positive transition of the clock (CLK) input, the device provides true data at the Q outputs if the clock-enable ( $\overline{CLKEN}$ ) input is low. If  $\overline{CLKEN}$  is high, no data is stored.

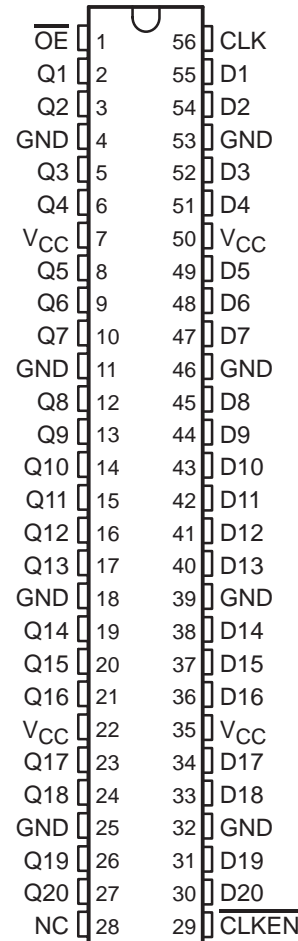
A buffered output-enable ( $\overline{OE}$ ) input places the 20 outputs in either a normal logic state (high or low) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.  $\overline{OE}$  does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16721 is characterized for operation from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .

**DGG, DGV, OR DL PACKAGE**  
**(TOP VIEW)**



NC – No internal connection



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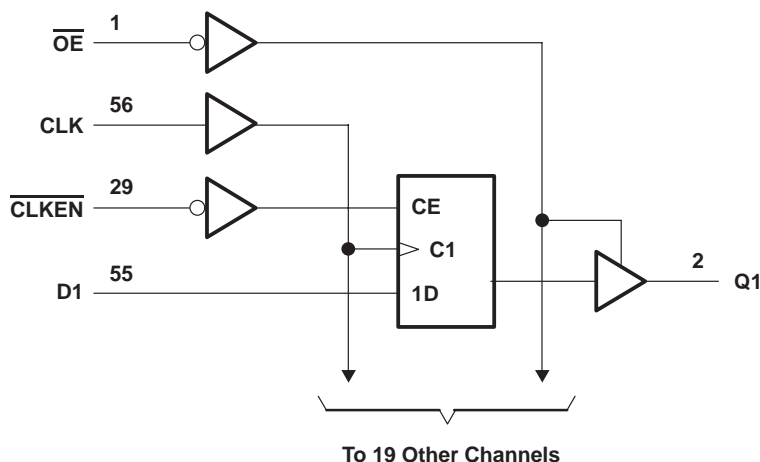
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**FUNCTION TABLE**  
(each flip-flop)

INPUTS				OUTPUT
$\overline{OE}$	$\overline{CLKEN}$	CLK	D	Q
L	H	X	X	$Q_0$
L	L	$\uparrow$	H	H
L	L	$\uparrow$	L	L
L	L	L or H	X	$Q_0$
H	X	X	X	Z

**logic diagram (positive logic)**



**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>**

Supply voltage range, $V_{CC}$	–0.5 V to 4.6 V
Input voltage range, $V_I$ (see Note 1)	–0.5 V to 4.6 V
Output voltage range, $V_O$ (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, $I_{IK}$ ( $V_I < 0$ )	–50 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ )	–50 mA
Continuous output current, $I_O$	$\pm 50$ mA
Continuous current through each $V_{CC}$ or GND	$\pm 100$ mA
Package thermal impedance, $\theta_{JA}$ (see Note 3):	
DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, $T_{stg}$	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
  2. This value is limited to 4.6 V maximum.
  3. The package thermal impedance is calculated in accordance with JESD 51.

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**recommended operating conditions (see Note 4)**

		MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage	1.65	3.6	V
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> = 1.65 V to 1.95 V	0.65 × V <sub>CC</sub>	V
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.7	
		V <sub>CC</sub> = 2.7 V to 3.6 V	2	
V <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 1.65 V to 1.95 V	0.35 × V <sub>CC</sub>	V
		V <sub>CC</sub> = 2.3 V to 2.7 V	0.7	
		V <sub>CC</sub> = 2.7 V to 3.6 V	0.8	
V <sub>I</sub>	Input voltage	0	V <sub>CC</sub>	V
V <sub>O</sub>	Output voltage	0	V <sub>CC</sub>	V
I <sub>OH</sub>	High-level output current	V <sub>CC</sub> = 1.65 V	–4	mA
		V <sub>CC</sub> = 2.3 V	–12	
		V <sub>CC</sub> = 2.7 V	–12	
		V <sub>CC</sub> = 3 V	–24	
I <sub>OL</sub>	Low-level output current	V <sub>CC</sub> = 1.65 V	4	mA
		V <sub>CC</sub> = 2.3 V	12	
		V <sub>CC</sub> = 2.7 V	12	
		V <sub>CC</sub> = 3 V	24	
Δt/Δv	Input transition rise or fall rate		10	ns/V
T <sub>A</sub>	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP†	MAX	UNIT
V <sub>OH</sub>	I <sub>OH</sub> = -100 μA	1.65 V to 3.6 V	V <sub>CC</sub> -0.2			V
	I <sub>OH</sub> = -4 mA	1.65 V	1.2			
	I <sub>OH</sub> = -6 mA	2.3 V	2			
	I <sub>OH</sub> = -12 mA	2.3 V	1.7			
		2.7 V	2.2			
	I <sub>OH</sub> = -24 mA	3 V	2.4			
V <sub>OL</sub>	I <sub>OL</sub> = 100 μA	1.65 V to 3.6 V			0.2	V
	I <sub>OL</sub> = 4 mA	1.65 V			0.45	
	I <sub>OL</sub> = 6 mA	2.3 V			0.4	
	I <sub>OL</sub> = 12 mA	2.3 V			0.7	
		2.7 V			0.4	
	I <sub>OL</sub> = 24 mA	3 V			0.55	
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	3.6 V			±5	μA
I <sub>I</sub> (hold)	V <sub>I</sub> = 0.58 V	1.65 V	25			μA
	V <sub>I</sub> = 1.07 V	1.65 V	-25			
	V <sub>I</sub> = 0.7 V	2.3 V	45			
	V <sub>I</sub> = 1.7 V	2.3 V	-45			
	V <sub>I</sub> = 0.8 V	3 V	75			
	V <sub>I</sub> = 2 V	3 V	-75			
	V <sub>I</sub> = 0 to 3.6 V‡	3.6 V			±500	
I <sub>OZ</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	3.6 V			±10	μA
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	3.6 V			40	μA
ΔI <sub>CC</sub>	One input at V <sub>CC</sub> - 0.6 V, Other inputs at V <sub>CC</sub> or GND	3 V to 3.6 V			750	μA
C <sub>i</sub>	Control inputs	V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V		3.5	pF
	Data inputs				6	
C <sub>O</sub>	Outputs	V <sub>O</sub> = V <sub>CC</sub> or GND	3.3 V		7	pF

† All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

**timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)**

		V <sub>CC</sub> = 1.8 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f <sub>clock</sub>	Clock frequency	§		150		150		150		MHz	
t <sub>w</sub>	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns	
t <sub>su</sub>	Setup time	Data before CLK↑	§		4		3.6		3.1		ns
		CLKEN before CLK↑	§		3.4		3.1		2.7		
t <sub>h</sub>	Hold time	Data after CLK↑	§		0		0		0		ns
		CLKEN after CLK↑	§		0		0		0		

§ This information was not available at the time of publication.



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**switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 1.8 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			†		150		150		150		MHz
t <sub>pd</sub>	CLK	Q		†	1	5.6	1	5.1	1	4.3	ns
t <sub>en</sub>	$\overline{OE}$	Q		†	1	6.1	1	5.8	1	4.8	ns
t <sub>dis</sub>	$\overline{OE}$	Q		†	1	5.5	1	4.7	1	4.4	ns

† This information was not available at the time of publication.

**operating characteristics, T<sub>A</sub> = 25°C**

PARAMETER		TEST CONDITIONS	V <sub>CC</sub> = 1.8 V	V <sub>CC</sub> = 2.5 V	V <sub>CC</sub> = 3.3 V	UNIT
			TYP	TYP	TYP	
C <sub>pd</sub>	Power dissipation capacitance	Outputs enabled	†	55	59	pF
		Outputs disabled	†	46	49	

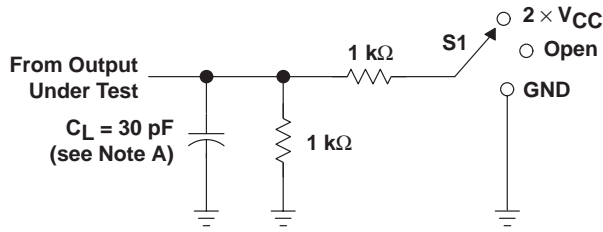
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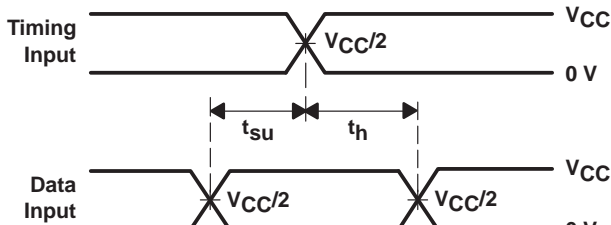
**PARAMETER MEASUREMENT INFORMATION**

$V_{CC} = 1.8\text{ V}$

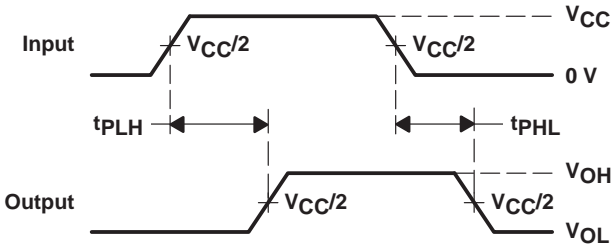


**LOAD CIRCUIT**

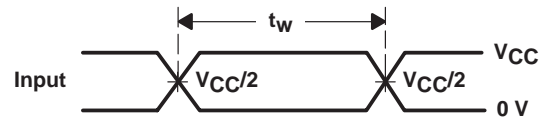
TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	$2 \times V_{CC}$
$t_{PHZ}/t_{PZH}$	GND



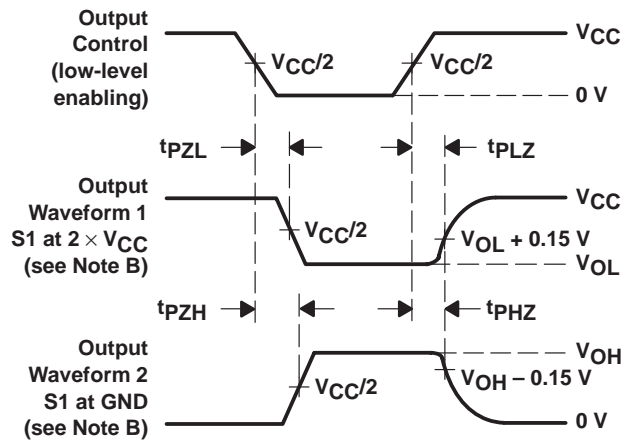
**VOLTAGE WAVEFORMS  
 SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS  
 PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS  
 PULSE DURATION**



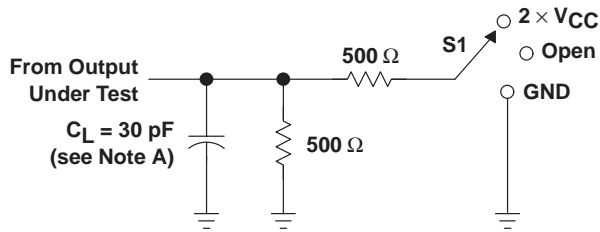
**VOLTAGE WAVEFORMS  
 ENABLE AND DISABLE TIMES**

- NOTES:
- A.  $C_L$  includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10\text{ MHz}$ ,  $Z_O = 50\ \Omega$ ,  $t_r \leq 2\text{ ns}$ ,  $t_f \leq 2\text{ ns}$ .
  - D. The outputs are measured one at a time with one transition per measurement.
  - E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
  - F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
  - G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

**Figure 1. Load Circuit and Voltage Waveforms**

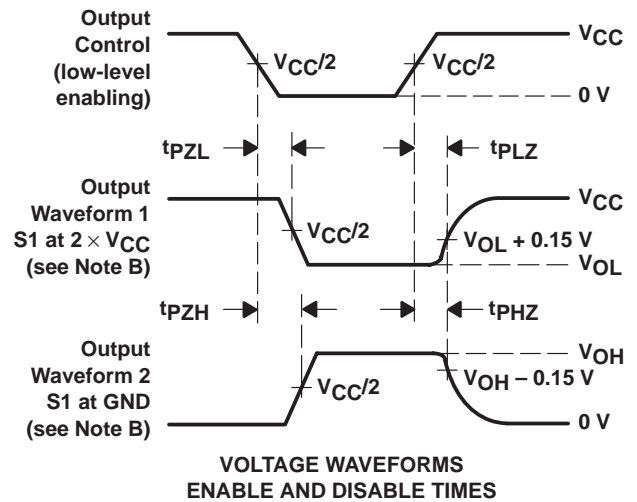
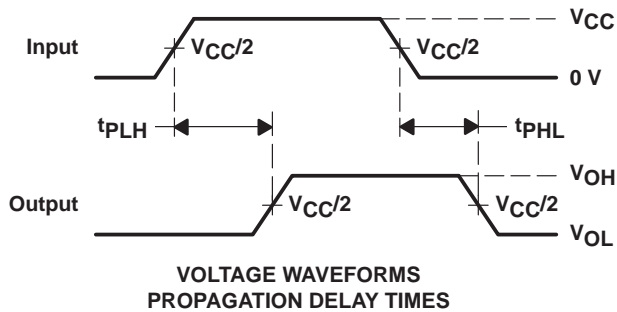
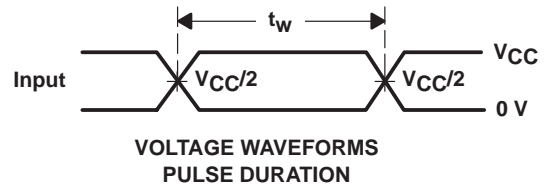
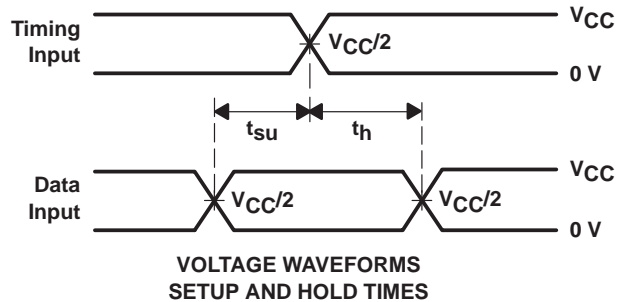
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$



LOAD CIRCUIT

TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	2 $\times V_{CC}$
$t_{PHZ}/t_{PZH}$	GND



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
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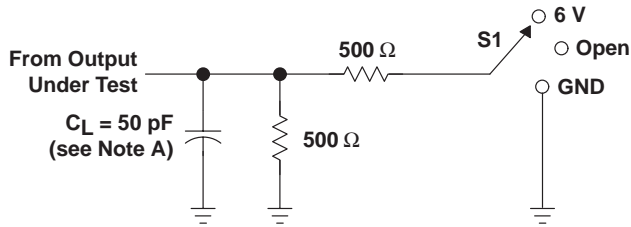
Figure 2. Load Circuit and Voltage Waveforms

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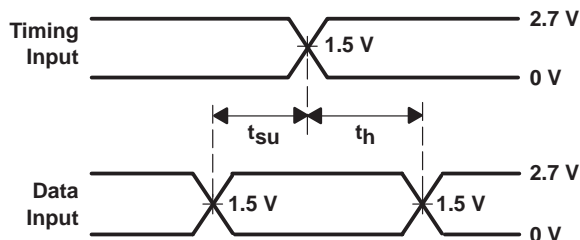
**PARAMETER MEASUREMENT INFORMATION**

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

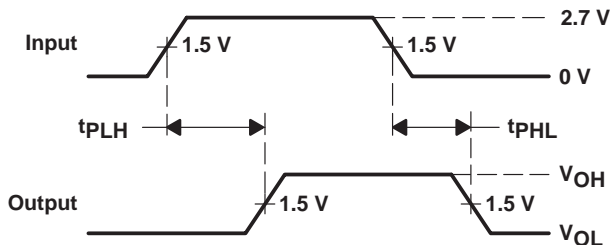


**LOAD CIRCUIT**

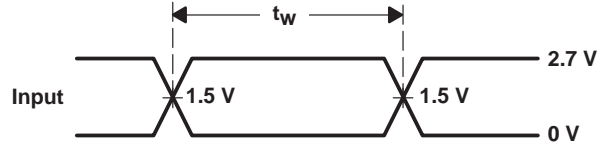
TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	6 V
$t_{PHZ}/t_{PHZ}$	GND



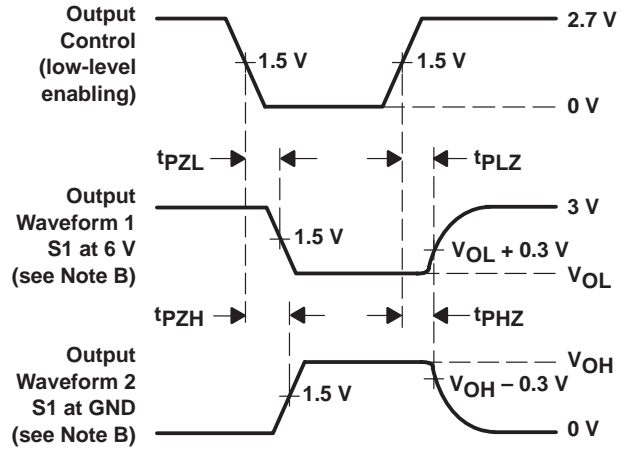
**VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES**



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**Figure 3. Load Circuit and Voltage Waveforms**



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